

RELIABILITY REPORT



**RELIABILITY DATA
LT1620 / LT1621**

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SSOP/TSSOP	36 36	9813	9813	36.09 36.09	0 0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	4,388	9636	0010	724.11	0
SSOP/TSSOP	794 5,182	9746	0212	30.80 754.92	0 0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	7,196	9637	0051	1,533.06	0
SSOP/TSSOP	804 8,000	9746	0212	80.70 1,613.76	0 0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,640	9637	0009	953.28	0
SSOP/TSSOP	731 3,371	9752	0345	73.10 1,026.38	0 0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 50.97 FITS

(3) Mean Time Between Failures in Years = 2,238

Note: 1 FIT = 1 Failure in One Billion Hours.